

<b>Notice of References Cited</b>	Application/Control No. 10/790,755	Applicant(s)/Patent Under Reexamination YAMANO ET AL.	
	Examiner Teresa M. Bonk	Art Unit 3725	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0083754	07-2002	Miyauchi et al.	72/349
*	B	US-5,544,517	08-1996	Shimizu, Keiichi	72/349
*	C	US-5,152,047	10-1992	Kojima et al.	29/411
*	D	US-6,089,072	07-2000	Fields, Brian	72/379.4
*	E	US-6,196,043	03-2001	Ehardt, Joseph T.	72/350
*	F	US-5,329,799	07-1994	Ito et al.	72/340
*	G	US-5,647,242	07-1997	Saunders, William T.	72/349
*	H	US-4,373,368	02-1983	Heijting, Hendrik G.	72/344
*	I	US-4,346,580	08-1982	Saunders, William T.	72/344
*	J	US-2,157,354	05-1939	SHERMAN DONALD W	72/349
*	K	US-4,312,695	01-1982	Willis, W. Coy	156/344
*	L	US-5,797,291	08-1998	Yamada, Mamoru	72/344
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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